 Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/670,618	FLOCK ET AL.	
Examiner	Art Unit	
Michael J. Hayes	3763	

	SEARCHED				
Class	Subclass	Date /	Examiner		
604	20-2 57-6 82-84	2 8/28/	Examiner OY MJ/		

INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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(INCLUDING SEARCH STRATEGY) DATE EXMF			
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